Stanford

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Publications

PUBLICATIONS

- **G-QED: Generalized QED Pre-silicon Verification beyond Non-Interfering Hardware Accelerators**
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- **LeGO: A Learning-Guided Obfuscation Framework for Hardware IP Protection** *IEEE TRANSACTIONS ON COMPUTER-AIDED DESIGN OF INTEGRATED CIRCUITS AND SYSTEMS*
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- **Proof-Stitch: Proof Combination for Divide-and-Conquer SAT Solvers**
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- **STT-MRAM for Low Power Access for Read-Intensive Parallel Deep-Learning Architectures**
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